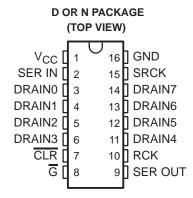
- Low r_{DS(on)} . . . 7 Ω Typ
- Avalanche Energy . . . 30 mJ
- Eight Power DMOS Transistor Outputs of 100-mA Continuous Current
- 250-mA Current Limit Capability
- ESD Protection . . . 2500 V
- Output Clamp Voltage . . . 33 V
- Devices Are Cascadable
- Low Power Consumption

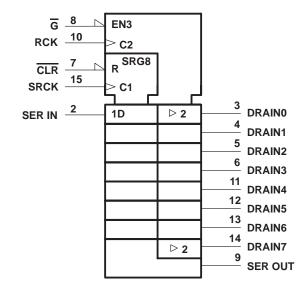
description

The TPIC6C595 is a monolithic, medium-voltage, low-current power 8-bit shift register designed for use in systems that require relatively moderate load power such as LEDs. The device contains a built-in voltage clamp on the outputs for inductive transient protection. Power driver applications include relays, solenoids, and other low-current or medium-voltage loads.

This device contains an 8-bit serial-in, parallel-out shift register that feeds an 8-bit D-type storage register. Data transfers through both the shift and storage registers on the rising edge of the shift register clock (SRCK) and the register clock (RCK), respectively. The device transfers data out the serial output (SER OUT) port on the rising edge of SRCK. The storage register transfers data to the output buffer when shift register clear (CLR) is high. When CLR is low, the input shift register is cleared. When output enable (G) is held high, all data in the output buffers is held low and all drain



logic symbol†



[†]This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

outputs are off. When \overline{G} is held low, data from the storage register is transparent to the output buffers. When data in the output buffers is low, the DMOS transistor outputs are off. When data is high, the DMOS transistor outputs have sink-current capability. The SER OUT allows for cascading of the data from the shift register to additional devices.



This device contains circuits to protect its inputs and outputs against damage due to high static voltages or electrostatic fields. These circuits have been qualified to protect this device against electrostatic discharges (ESD) of up to 2 kV according to MIL-STD-883C, Method 3015; however, it is advised that precautions be taken to avoid application of any voltage higher than maximum-rated voltages to these high-impedance circuits. During storage or handling, the device leads should be shorted together or the device should be placed in conductive foam. In a circuit, unused inputs should always be connected to an appropriated logic voltage level, preferably either VCC or ground. Specific guidelines for handling devices of this type are contained in the publication *Guidelines for Handling Electrostatic-Discharge-Sensitive (ESDS) Devices and Assemblies* available from Texas Instruments.



Please be aware that an important notice concerning availability, standard warranty, and use in critical applications of Texas Instruments semiconductor products and disclaimers thereto appears at the end of this data sheet.



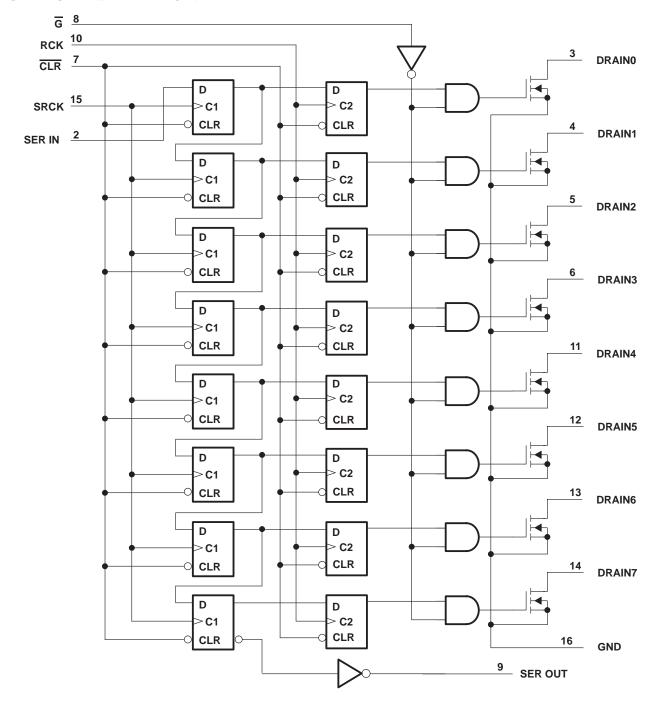
SLIS061B - JULY 1998 - REVISED MAY 2004

description (continued)

Outputs are low-side, open-drain DMOS transistors with output ratings of 33 V and 100 mA continuous sink-current capability. Each output provides a 250-mA maximum current limit at T_C = 25°C. The current limit decreases as the junction temperature increases for additional device protection. The device also provides up to 2500 V of ESD protection when tested using the human-body model and the 200-V machine model.

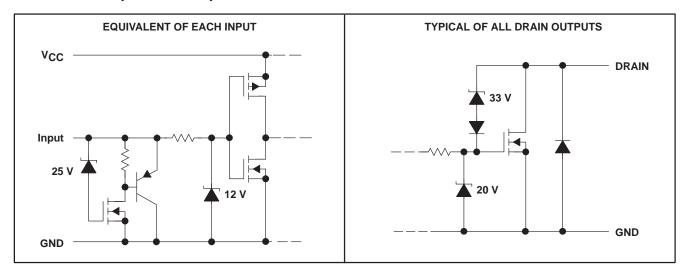
The TPIC6C595 is characterized for operation over the operating case temperature range of -40°C to 125°C.

logic diagram (positive logic)





schematic of inputs and outputs



absolute maximum ratings over recommended operating case temperature range (unless otherwise noted) †

Logic supply voltage, V _{CC} (see Note 1)	
Logic input voltage range, V _I	0.3 V to 7 V
Power DMOS drain-to-source voltage, V _{DS} (see Note 2)	33 V
Continuous source-to-drain diode anode current	
Pulsed source-to-drain diode anode current (see Note 3)	500 mA
Pulsed drain current, each output, all outputs on, I _D , T _C = 25°C (see Note 3)	250 mA
Continuous drain current, each output, all outputs on, I _D , T _C = 25°C	100 mA
Peak drain current single output, I _{DM} ,T _C = 25°C (see Note 3)	250 mA
Single-pulse avalanche energy, E _{AS} (see Figure 4)	30 mJ
Avalanche current, I _{AS} (see Note 4)	200 mA
Continuous total dissipation	See Dissipation Rating Table
Operating virtual junction temperature range, T _J	–40°C to 150°C
Operating case temperature range, T _C	–40°C to 125°C
Storage temperature range, T _{stq}	65°C to 150°C
Lead temperature 1,6 mm (1/16 inch) from case for 10 seconds	260°C

[†] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

- NOTES: 1. All voltage values are with respect to GND.
 - 2. Each power DMOS source is internally connected to GND.
 - 3. Pulse duration \leq 100 μ s and duty cycle \leq 2%.
 - 4. DRAIN supply voltage = 15 V, starting junction temperature (T_{JS}) = 25°C, L = 1.5 H, I_{AS} = 200 mA (see Figure 4).

DISSIPATION RATING TABLE

PACKAGE	$T_C \le 25^{\circ}C$ POWER RATING	DERATING FACTOR ABOVE T _C = 25°C	T _C = 125°C POWER RATING
D	1087 mW	8.7 mW/°C	217 mW
N	1470 mW	11.7 mW/°C	294 mW



TPIC6C595 POWER LOGIC 8-BIT SHIFT REGISTER

SLIS061B - JULY 1998 - REVISED MAY 2004

recommended operating conditions

	MIN	MAX	UNIT
Logic supply voltage, V _{CC}	4.5	5.5	V
High-level input voltage, V _{IH}	0.85 V _{CC}		V
Low-level input voltage, V _{IL}		0.15 V _{CC}	V
Pulsed drain output current, T _C = 25°C, V _{CC} = 5 V, all outputs on (see Notes 3 and 5 and Figure 11)		250	mA
Setup time, SER IN high before SRCK↑, t _{SU} (see Figure 2)	20		ns
Hold time, SER IN high after SRCK↑, th (see Figure 2)	20		ns
Pulse duration, t _W (see Figure 2)	40		ns
Operating case temperature, T _C	-40	125	°C

electrical characteristics, $V_{CC} = 5 \text{ V}$, $T_{C} = 25^{\circ}\text{C}$ (unless otherwise noted)

	PARAMETER	TEST (CONDITIONS	MIN	TYP	MAX	UNIT
V(BR)DSX	Drain-to-source breakdown voltage	$I_D = 1 \text{ mA}$		33	37		V
V _{SD}	Source-to-drain diode forward voltage	I _F = 100 mA			0.85	1.2	V
		$I_{OH} = -20 \mu A$,	V _{CC} = 4.5 V	4.4	4.49		.,
VOH	High-level output voltage, SER OUT	$I_{OH} = -4 \text{ mA},$	V _{CC} = 4.5 V	4	4.2		V
		$I_{OL} = 20 \mu A$,	V _{CC} = 4.5 V		0.005	0.1	.,
VOL	Low-level output voltage, SER OUT	$I_{OL} = 4 \text{ mA},$	V _{CC} = 4.5 V		0.3	0.5	V
lιΗ	High-level input current	$V_{CC} = 5.5 \text{ V},$	$V_I = V_{CC}$			1	μΑ
I _{IL}	Low-level input current	$V_{CC} = 5.5 \text{ V},$	V _I = 0			-1	μΑ
	Logic supply current	V _{CC} = 5.5 V	All outputs off		20	200	
Icc			All outputs on		150	500	μΑ
I _{CC(FRQ)}	Logic supply current at frequency	fSRCK = 5 MHz, All outputs off,	C _L = 30 pF, See Figures 2 and 6		1.2	5	mA
I _N	Nominal current	$V_{DS(on)} = 0.5 \text{ V},$ $T_{C} = 85^{\circ}\text{C},$	$I_N = I_D$, See Notes 5, 6, and 7		90		mA
		$V_{DS} = 30 \text{ V},$	V _{CC} = 5.5 V		0.1	0.2	
IDSX	Off-state drain current	V _{DS} = 30 V, T _C = 125°C	V _{CC} = 5.5 V,		0.15	0.3	μΑ
		I _D = 50 mA, V _{CC} = 4.5 V	6.5	9			
rDS(on)	Static drain-source on-state resistance	I _D = 50 mA, T _C = 125°C, V _{CC} = 4.5 V	See Notes 5 and 6 and Figures 7 and 8		9.9	12	Ω
		I _D = 100 mA, V _{CC} = 4.5 V			6.8	10	

NOTES: 3. Pulse duration $\leq 100 \,\mu s$ and duty cycle $\leq 2\%$.

- 5. Technique should limit $T_J T_C$ to 10°C maximum.
- 6. These parameters are measured with voltage-sensing contacts separate from the current-carrying contacts.
- Nominal current is defined for a consistent comparison between devices from different sources. It is the current that produces a voltage drop of 0.5 V at T_C = 85°C.



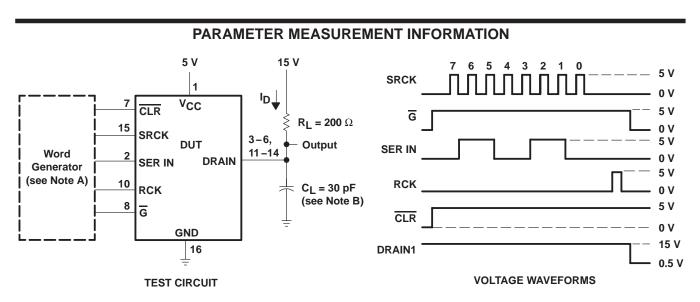
switching characteristics, $V_{CC} = 5 \text{ V}$, $T_{C} = 25^{\circ}\text{C}$

PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNIT
^t PLH	Propagation delay time, low-to-high-level output from \overline{G}			80		ns
tPHL	Propagation delay time, high-to-low-level output from \overline{G}]		50		ns
tpd	Propagation delay time, SRCK to SEROUT	C _L = 30 pF, I _D = 75 mA, See Figures 1, 2, and 9		20		ns
t _r	Rise time, drain output	garee 1, 2, and e		100		ns
t _f	Fall time, drain output			80		ns
ta	Reverse-recovery-current rise time	$I_F = 100 \text{ mA}, \qquad \text{di/dt} = 10 \text{ A/}\mu\text{s},$		100		
t _{rr}	Reverse-recovery time	See Notes 5 and 6 and Figure 3		120	·	ns

NOTES: 5. Technique should limit $T_J - T_C$ to 10°C maximum.

thermal resistance

PARAMETER		TEST CONDITIONS	MIN	MAX	UNIT
R _{θJA} Thermal resistance, junction-to-ambient	D package	All 8 outputs with equal power		115	°C/W
	Thermal resistance, junction-to-ambient	N package	All o outputs with equal power		85



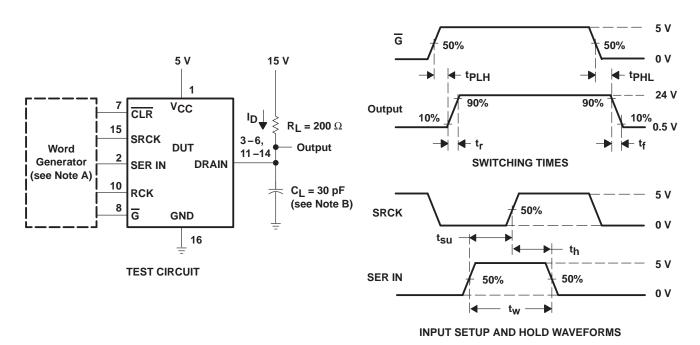
NOTES: A. The word generator has the following characteristics: $t_{\Gamma} \le 10$ ns, $t_{W} = 300$ ns, pulsed repetition rate (PRR) = 5 kHz, $Z_{O} = 50~\Omega$.

B. C_L includes probe and jig capacitance.

Figure 1. Resistive-Load Test Circuit and Voltage Waveforms

^{6.} These parameters are measured with voltage-sensing contacts separate from the current-carrying contacts.

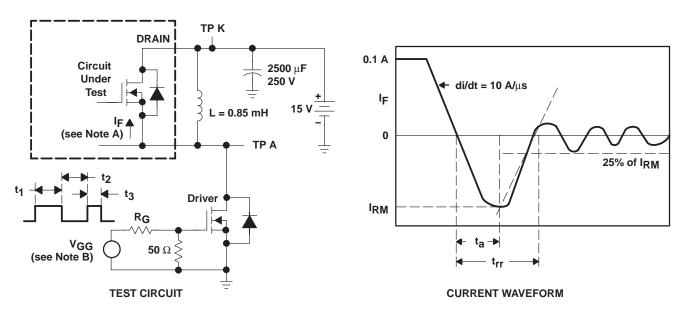
PARAMETER MEASUREMENT INFORMATION



NOTES: A. The word generator has the following characteristics: $t_{\Gamma} \le 10$ ns, $t_{W} = 300$ ns, pulsed repetition rate (PRR) = 5 kHz, $Z_{O} = 50 \ \Omega$.

B. CL includes probe and jig capacitance.

Figure 2. Test Circuit, Switching Times, and Voltage Waveforms



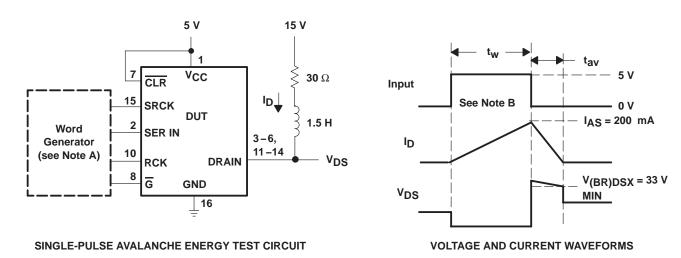
NOTES: A. The DRAIN terminal under test is connected to the TP K test point. All other terminals are connected together and connected to the TP A test point.

B. The V_{GG} amplitude and R_G are adjusted for di/dt = 10 A/ μ s. A V_{GG} double-pulse train is used to set I_F = 0.1 A, where t₁ = 10 μ s, t₂ = 7 μ s, and t₃ = 3 μ s.

Figure 3. Reverse-Recovery-Current Test Circuit and Waveforms of Source-to-Drain Diode



PARAMETER MEASUREMENT INFORMATION

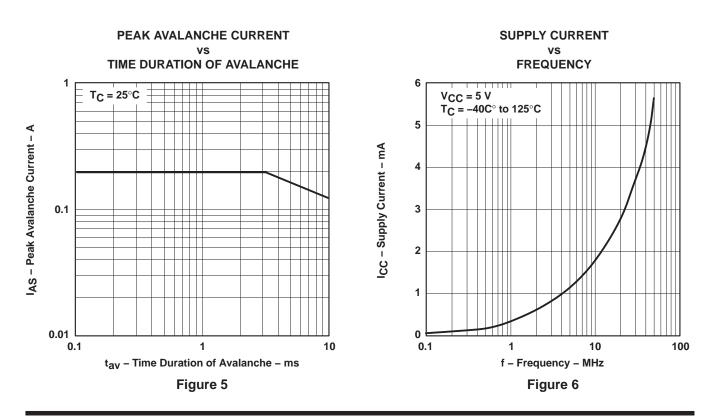


NOTES: A. The word generator has the following characteristics: $t_f \le 10$ ns, $t_f \le 10$ ns, $Z_O = 50 \Omega$.

B. Input pulse duration, t_W , is increased until peak current $I_{AS} = 200$ mA. Energy test level is defined as $E_{AS} = I_{AS} \times V_{(BR)DSX} \times t_{aV}/2 = 30$ mJ.

Figure 4. Single-Pulse Avalanche Energy Test Circuit and Waveforms

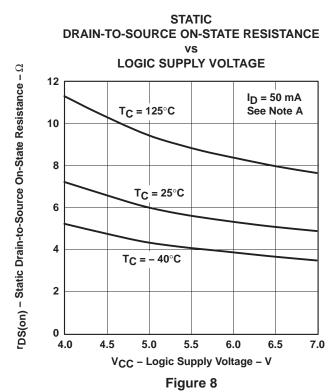
TYPICAL CHARACTERISTICS



TYPICAL CHARACTERISTICS

DRAIN-TO-SOURCE ON-STATE RESISTANCE DRAIN CURRENT rDS(on) – Drain-to-Source On-State Resistance – Ω 30 $V_{CC} = 5 V$ See Note A 25 T_C = 125°C 20 15 10 $T_C = 25^{\circ}C$ 5 $T_C = -40^{\circ}C$ 70 130 150 190 250 50 110 170 ID - Drain Current - mA

Figure 7



SWITCHING TIME CASE TEMPERATURE 140 $I_D = 75 \text{ mA}$ See Note A tr 120 tf 100 Switching Time - ns 80 ^tPLH 60 ^tPHL 40 20 0 -25 125 -50 100 T_C - Case Temperature - °C Figure 9

NOTE A: Technique should limit $T_J - T_C$ to 10°C maximum.



THERMAL INFORMATION

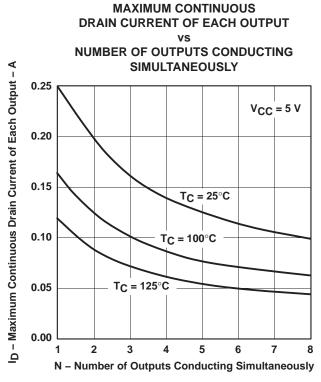


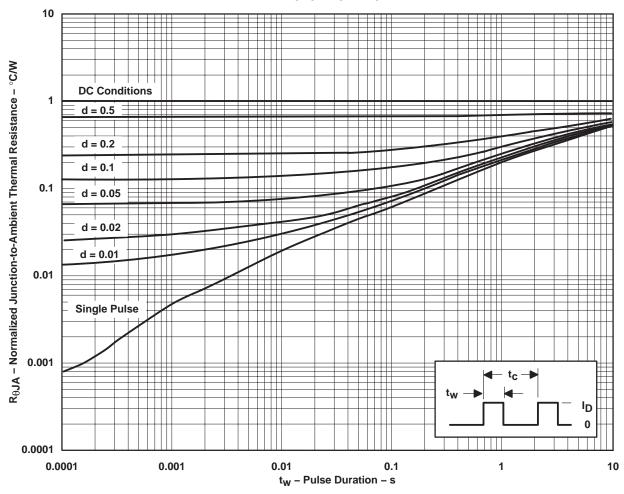
Figure 10

MAXIMUM PEAK DRAIN CURRENT OF EACH OUTPUT NUMBER OF OUTPUTS CONDUCTING **SIMULTANEOUSLY** ID - Maximum Peak Drain Current of Each Output - A 0.30 d = 10%0.25 d = 20%0.20 d = 50%0.15 d = 80%0.10 $V_{CC} = 5 V$ 0.05 T_C = 25°C $d = t_W/t_{period}$ = 1 ms/t_{period} 0.00 2 4 5 6 7 3 8 N - Number of Outputs Conducting Simultaneously

Figure 11

THERMAL INFORMATION

D PACKAGE[†] NORMALIZED JUNCTION-TO-AMBIENT THERMAL RESISTANCE vs PULSE DURATION



† Device mounted on FR4 printed-circuit board with no heat sink

 $\begin{aligned} \text{NOTES:} \quad Z_{\theta A}(t) &= r(t) \; R_{\theta JA} \\ t_W &= \text{pulse duration} \\ t_C &= \text{cycle time} \\ d &= \text{duty cycle} = t_W/t_C \end{aligned}$

Figure 12



IMPORTANT NOTICE

Texas Instruments Incorporated and its subsidiaries (TI) reserve the right to make corrections, modifications, enhancements, improvements, and other changes to its products and services at any time and to discontinue any product or service without notice. Customers should obtain the latest relevant information before placing orders and should verify that such information is current and complete. All products are sold subject to TI's terms and conditions of sale supplied at the time of order acknowledgment.

TI warrants performance of its hardware products to the specifications applicable at the time of sale in accordance with TI's standard warranty. Testing and other quality control techniques are used to the extent TI deems necessary to support this warranty. Except where mandated by government requirements, testing of all parameters of each product is not necessarily performed.

TI assumes no liability for applications assistance or customer product design. Customers are responsible for their products and applications using TI components. To minimize the risks associated with customer products and applications, customers should provide adequate design and operating safeguards.

TI does not warrant or represent that any license, either express or implied, is granted under any TI patent right, copyright, mask work right, or other TI intellectual property right relating to any combination, machine, or process in which TI products or services are used. Information published by TI regarding third-party products or services does not constitute a license from TI to use such products or services or a warranty or endorsement thereof. Use of such information may require a license from a third party under the patents or other intellectual property of the third party, or a license from TI under the patents or other intellectual property of TI.

Reproduction of information in TI data books or data sheets is permissible only if reproduction is without alteration and is accompanied by all associated warranties, conditions, limitations, and notices. Reproduction of this information with alteration is an unfair and deceptive business practice. TI is not responsible or liable for such altered documentation.

Resale of TI products or services with statements different from or beyond the parameters stated by TI for that product or service voids all express and any implied warranties for the associated TI product or service and is an unfair and deceptive business practice. TI is not responsible or liable for any such statements.

Following are URLs where you can obtain information on other Texas Instruments products and application solutions:

e
d
trol
work
d trol wo

Mailing Address: Texas Instruments

Post Office Box 655303 Dallas, Texas 75265

Copyright © 2004, Texas Instruments Incorporated